

## 2014 LTPP Operational Flexibility Modeling Workshop | June 6, 2014, 10am – 4pm

CPUC Auditorium, 505 Van Ness Avenue, San Francisco, CA

Teleconference number: 866-778-0461 Participant code: 3664376

WebEx: <https://van.webex.com/van/j.php?MTID=mac9c73b1154c7d4f92a7e36dec14e76b>

Meeting number: 747 724 548

Meeting password: ltpm

**For technical difficulties during the workshop, contact Patrick Young at [patrick.young@cpuc.ca.gov](mailto:patrick.young@cpuc.ca.gov)**

### Purpose

This workshop is for the modeling parties to inform other parties about the details and complexities of operational flexibility modeling in order to increase transparency, and better equip parties to interpret modeling results and prepare written testimony. Energy Division staff will facilitate presentations by SCE and CAISO, parties conducting operational flexibility modeling of the 2024 grid and intending to submit modeling results as testimony to inform the CPUC LTPP Proceeding (R.13-12-010) Phase 1a determination of system need.

### Agenda

Time	Speaker	Topic
10:00 – 10:15	Patrick Young, Energy Division	Introduction / Schedule
10:15 – 11:25	Megan Mao, SCE	Describe SCE's analysis objectives. Define Loss of Load event and Overgeneration event. Describe how to interpret result metrics such as heat maps, confidence intervals, and percentiles.
11:25- 12:10	Erin Childs, SCE	Introduce SCE's LTPP analysis model framework and principles. Define stochastic analysis and describe study objectives. Describe the model's implementation of overgeneration analysis. Describe the model's implementation of hydro generation.
12:10 – 1:10		Lunch Break
1:10 – 1:45	Martin Blagaich, SCE	Define forecast error and describe the model's implementation of forecast error. Describe the model's use of sample stratification and how convergence in results will be demonstrated.
1:45 – 2:05	SCE	Discuss next steps and timeline for SCE's analysis. Q and A session.
2:05 – 2:15		Break
2:15 – 4:00	Shucheng Liu, CAISO	Discuss assumptions and data sources for the ISO deterministic model.